

MOS INTEGRATED CIRCUIT $\mu PD23C32000L$

32M-BIT MASK-PROGRAMMABLE ROM 4M-WORD BY 8-BIT (BYTE MODE) / 2M-WORD BY 16-BIT (WORD MODE)

Description

The μ PD23C32000L is a 33,554,432 bits mask-programmable ROM. The word organization is selectable (BYTE mode : 4,194,304 words by 8 bits, WORD mode : 2,097,152 words by 16 bits).

The active levels of OE (Output Enable Input) can be selected with mask-option.

The μ PD23C32000L are packed in 44-pin plastic SOP, 48-pin plastic TSOP (I), and 44-pin plastic TSOP (II).

Features

• Word organization

4,194,304 words by 8 bits (BYTE mode)

2,097,152 words by 16 bits (WORD mode)

• Operating supply voltage: Vcc = 2.7 to 3.6 V

Operating supply voltage Vcc	Access time ns (MAX.)	Power supply current (Active mode) mA (MAX.)	Standby current (CMOS level input) µA (MAX.)	
3.0 V ± 0.3 V	140	35	30	
3.3 V ± 0.3 V	120	40	30	

Ordering Information

(xxx: ROM code suffix No.)

Part number	Package
μPD23C32000LGX-xxx	44-pin plastic SOP (600 mil)
μ PD23C32000LGY-xxx-MJH	48-pin plastic TSOP (I) (12 \times 18 mm) (Normal bent)
μ PD23C32000LGY-xxx-MKH	48-pin plastic TSOP (I) (12 \times 18 mm) (Reverse bent)
μPD23C32000LG5-xxx-7JF	44-pin plastic TSOP (II) (400 mil) (Normal bent)

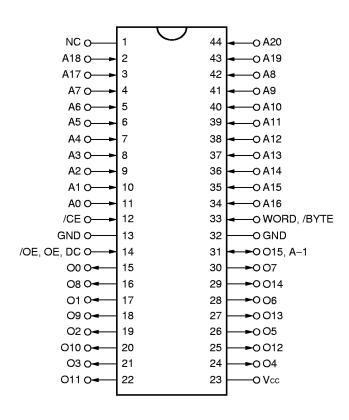
The information in this document is subject to change without notice.



Pin Configuration (Marking Side)

/xxx indicates active low signal.

44-pin Plastic SOP (600 mil) [μ PD23C32000LGX]



A0 - A20 : Address inputs
O0 - O7, O8 - O14 : Data Outputs

O15, A-1 : Data 15 Output (WORD mode),

LSB Address input (BYTE mode)

WORD, /BYTE : Mode select
/CE : Chip Enable
/OE, OE : Output Enable
Vcc : Supply Voltage

GND : Ground

NC Note 1 : No Connection

IC Note 2 : Internal Connection

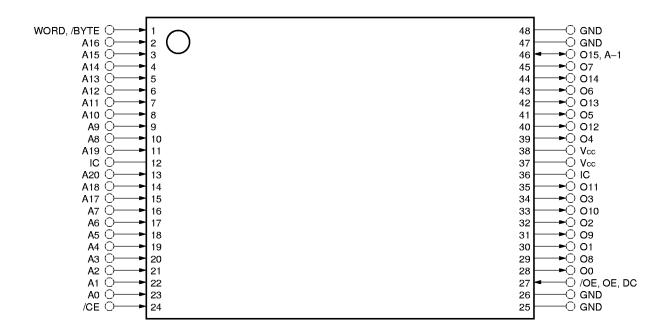
DC : Don't Care

Notes 1. Some signals can be applied because this pin is not connected to the inside of the chip.

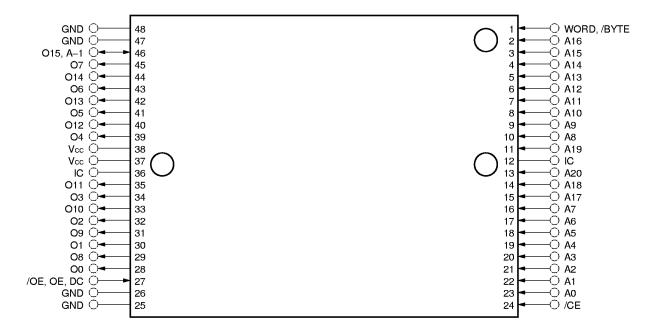
2. Leave this pin unconnected or connect to GND.



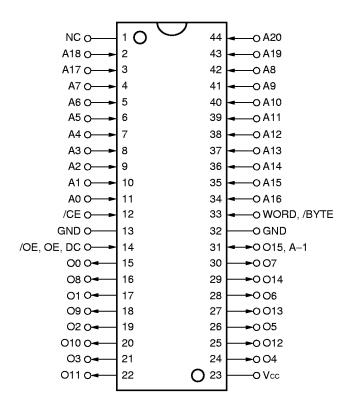
48-pin Plastic TSOP (I) (12 \times 18 mm) (Normal Bent) [μ PD23C32000LGY-MJH]



48-pin Plastic TSOP (I) (12 \times 18 mm) (Reverse Bent) [μ PD23C32000LGY-MKH]



44-pin Plastic TSOP (II) (400 mil) (Normal Bent) $[~\mu {\rm PD23C32000LG5\text{-}7JF}~]$



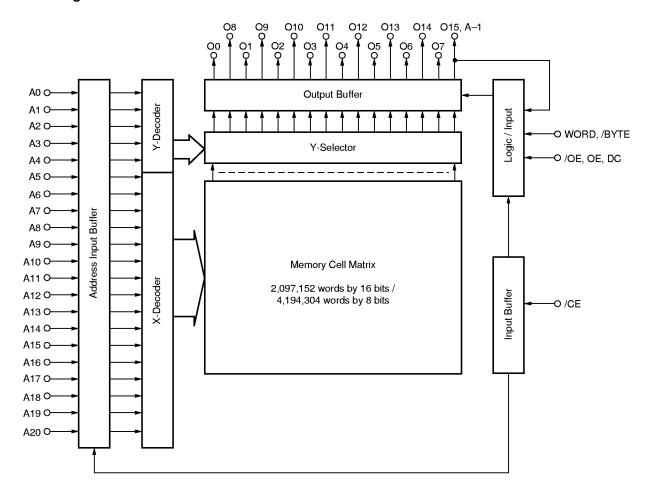


Input / Output Pin Functions

Pin name	Input / Output	Function
WORD, /BYTE	Input	The pin for switching WORD mode and BYTE mode. High level: WORD mode (2M-word by 16-bit) Low level: BYTE mode (4M-word by 8-bit)
A0 to A20 (Address input)	Input	Address bus. A0 to A20 are used differently in the WORD mode and the BYTE mode. WORD mode (2M-word by 16-bit) A0 to A20 are used as 21 bits address signals. BYTE mode (4M-word by 8-bit) A0 to A20 are used as the upper 21 bits of total 22 bits of address signal. (The least significant bit (A-1) is combined to O15.)
O0 to O7, O8 to O14 (Data output)	Output	Output data bus. O0 to O7, O8 to O14 are used differently in the WORD mode and the BYTE mode. WORD mode (2M-word by 16-bit) The lower 15 bits of 16 bits data outputs to O0 to O14. (The most significant bit (O15) combined to A-1.) BYTE mode (4M-word by 8-bit) 8 bits data outputs to O0 to O7 and also O8 to O14 are high impedance.
O15, A-1 (Data output 15, LSB address input)	Output, Input	O15, A-1 are used differently in the WORD mode and the BYTE mode. WORD mode (2M-word by 16-bit) The most significant output data bus (O15). BYTE mode (4M-word by 8-bit) The least significant address bus (A-1).
/CE (Chip Enable)	Input	Chip activating signal. When the OE is active, output states are following. High level: High impedance Low level: Data out
/OE, OE, DC (Output Enable, Don't Care)	Input	Output enable signal. The active level of OE is mask option. The active level of OE can be selected from high active, low active and Don't care at order.
Vcc	_	Supply voltage
GND	-	Ground
NC	-	Not internally connected (The signal can be connected).
IC	-	Internally connected (Leave this pin unconnected or connect to GND).



Block Diagram





Mask Option

The active levels of output enable pin (/OE, OE, DC) are mask programmable and optional, and can be selected from among "0" "1" "x" shown in the table below.

Option	/OE, OE, DC	OE active level
0	/OE	L
1	OE	Н
×	DC	Don't care

Operation modes for each option are shown in the tables below.

Operation mode (Option: 0)

/CE	/OE	Mode	Output state
L	L	Active	Data out
	Н		High impedance
Н	H or L	Standby	High impedance

Operation mode (Option: 1)

/CE	OE	Mode	Output state
L	L	Active	High impedance
	Н		Data out
Н	H or L	Standby	High impedance

Operation mode (Option : \times)

/CE	DC	Mode	Output state
L	H or L	Active	Data out
Н	H or L	Standby	High impedance

Remark L: Low level input

H: High level input



Electrical Specifications

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Supply voltage	Vcc		-0.3 to +4.6	٧
Input voltage	Vı		-0.3 to Vcc + 0.3	٧
Output voltage	Vo		-0.3 to Vcc + 0.3	٧
Operating ambient temperature	Та		-10 to +70	°C
Storage temperature	Tstg		−65 to +150	ů

Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Capacitance (TA = 25 °C)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	Ci	f = 1 MHz			10	pF
Output capacitance	Со				12	pF

DC Characteristics (TA = -10 to +70 °C, Vcc = 2.7 to 3.6 V)

Parameter	Symbol	Test con	dition	MIN.	TYP.	MAX.	Unit
High level input voltage	ViH			2.0		Vcc + 0.3	٧
Low level input voltage	VIL	Vcc = 3.0 V ± 0.3 V		-0.3		+0.5	٧
		Vcc = 3.3 V ± 0.3 V		-0.3		+0.8	
High level output voltage	Vон	Іон = −100 μА		2.4			٧
Low level output voltage	Vol	loL = 2.1 mA	loL = 2.1 mA			0.4	٧
Input leakage current	lu	Vı = 0 V to Vcc	Vi = 0 V to Vcc			+10	μΑ
Output leakage current	ILO	Vo = 0 V to Vcc, Chip de	Vo = 0 V to Vcc, Chip deselected			+10	μΑ
Power supply current	Icc ₁	/CE = V _{IL} (Active mode), $V_{CC} = 3.0 \text{ V} \pm 0.3 \text{ V}$				35	mA
		lo = 0 mA	Vcc = 3.3 V ± 0.3 V			40	
Standby current	Іссз	/CE = Vcc - 0.2 V (Stand	dby mode)			30	μΑ



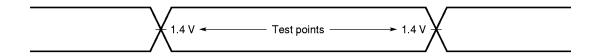
AC Characteristics (Ta = -10 to +70 °C, Vcc = 2.7 to 3.6 V)

Parameter	Symbol	Test condition	Vcc =	$Vcc = 3.0 V \pm 0.3 V$		Vcc =	Unit		
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Address access time	tacc				140			120	ns
Chip enable access time	tce				140			120	ns
Output enable access time	toe				50			40	ns
Output hold time	tон		0			0			ns
Output disable time	tof		0		30	0		25	ns
WORD, /BYTE access time	twв				140			120	ns

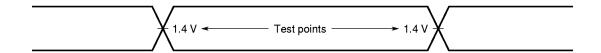
Remark top is the time from inactivation of /CE or /OE, OE to high-impedance state output.

AC Test Conditions

Input Waveform (Rise / Fall Time ≤ 5 ns)



Output Waveform

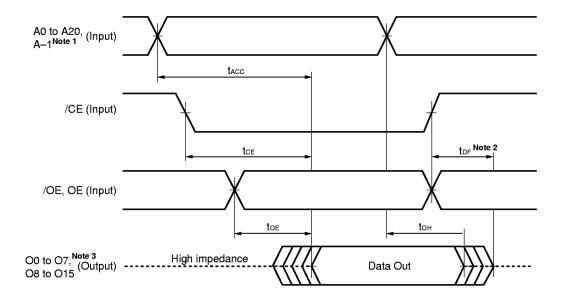


Output Load

1 TTL + 100 pF

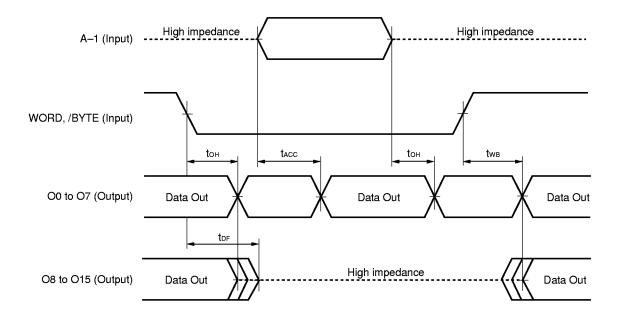


Read Cycle Timing Chart



- Notes 1. During WORD mode, A-1 is O15.
 - 2. tDF is specified when one of /CE, /OE, OE is inactivated.
 - 3. During BYTE mode, O8 to O14 are high impedance and O15 is A-1.

WORD, /BYTE Switch Timing Chart



Remark /OE, OE and /CE : Active.

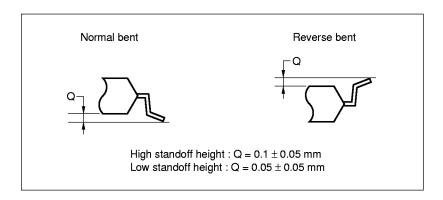


Notice of Change in 48-Pin TSOP (I) Standoff Height

We are changing the 48-pin TSOP (I) standoff height 0.05 \pm 0.05 mm (low standoff height) to 0.1 \pm 0.05 mm (high standoff height). Each lot version is identified by the fifth character of the lot number.

Difference Between High Standoff Height and Low Standoff Height

Detail of Lead End

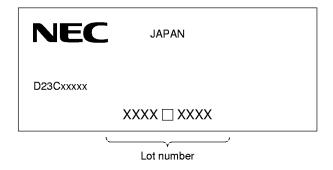


Identification of Each Lot Version

Each lot version is identified by the fifth character of the lot number.

Fifth character of the lot number	Lot version	Standoff height
L	L version	$0.1\pm0.05~\text{mm}$ (high standoff height)
К	K version	0.05 \pm 0.05 mm (low standoff height)
E	E version	

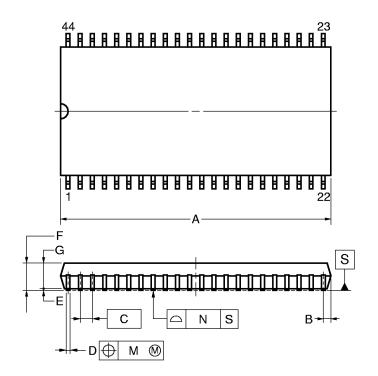
Marking Example





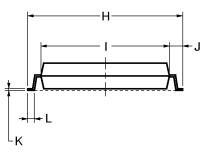
Package Drawings

44 PIN PLASTIC SOP (600 mil)



detail of lead end





NOTE

- 1. Controlling dimension millimeter.
- 2. Each lead centerline is located within 0.12 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

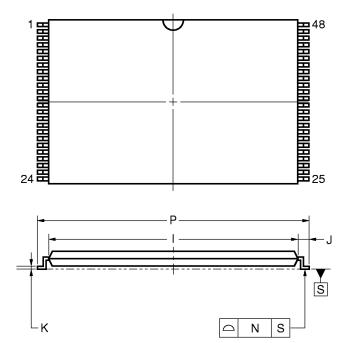
ITEM	MILLIMETERS	INCHES
Α	27.83 ^{+0.4} _{-0.05}	1.096 ^{+0.016} -0.003
В	0.78 MAX.	0.031 MAX.
С	1.27 (T.P.)	0.050 (T.P.)
D	$0.42^{+0.08}_{-0.07}$	$0.017^{+0.003}_{-0.004}$
E	0.15±0.1	0.006±0.004
F	3.0 MAX.	0.119 MAX.
G	2.7±0.05	$0.106^{+0.003}_{-0.002}$
Н	16.04±0.3	0.631 ^{+0.013} -0.012
ı	13.24±0.1	$0.521^{+0.005}_{-0.004}$
J	1.4±0.2	0.055±0.008
K	$0.22^{+0.08}_{-0.07}$	$0.009^{+0.003}_{-0.004}$
L	0.8±0.2	$0.031^{+0.009}_{-0.008}$
М	0.12	0.005
N	0.10	0.004
Р	3° +7° -3°	3° +7°.
		DAAGY EO GOOA 2

P44GX-50-600A-3



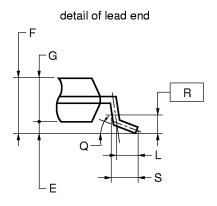
L Version : High Standoff Height

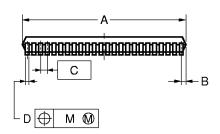
48 PIN PLASTIC TSOP (I) (12×18)





- 1. Controlling dimension Millimeter.
- Each lead centerline is located within 0.10 mm (0.004 inch) of its true position (T.P.) at maximum material condition.
- 3. "A" excludes mold flash. (Includes mold flash: 12.4 mm MAX. <0.489 inch MAX.>)





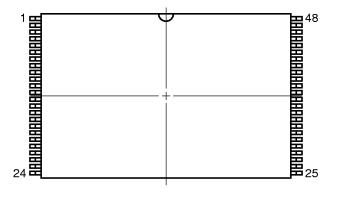
ITEM	MILLIMETERS	INCHES
Α	12.0±0.1	$0.472^{+0.005}_{-0.004}$
В	0.45 MAX.	0.018 MAX.
С	0.5 (T.P.)	0.020 (T.P.)
D	0.22±0.05	$0.009^{+0.002}_{-0.003}$
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	1.0±0.05	$0.039^{+0.003}_{-0.002}$
ı	16.4±0.1	$0.646^{+0.004}_{-0.005}$
J	0.8±0.2	$0.031^{+0.009}_{-0.008}$
K	0.145±0.05	$0.006^{+0.002}_{-0.003}$
L	0.5	0.020
М	0.10	0.004
N	0.10	0.004
Р	18.0±0.2	$0.709^{+0.008}_{-0.009}$
Q	3°+5°	3°+5°°
R	0.25	0.010
S	0.60±0.15	$0.024^{+0.006}_{-0.007}$

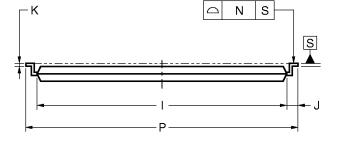
S48GY-50-MJH1



L Version: High Standoff Height

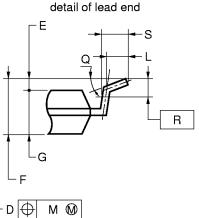
48 PIN PLASTIC TSOP (I) (12×18)

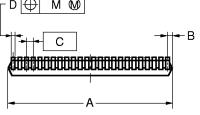




NOTES

- 1. Controlling dimension Millimeter.
- 2. Each lead centerline is located within 0.10 mm (0.004 inch) of its true position (T.P.) at maximum material condition.
- 3. "A" excludes mold flash. (Includes mold flash : 12.4 mm MAX. <0.489 inch MAX.>)





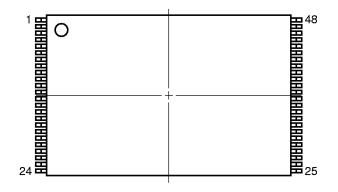
ITEM	MILLIMETERS	INCHES
Α	12.0±0.1	$0.472^{+0.005}_{-0.004}$
В	0.45 MAX.	0.018 MAX.
С	0.5 (T.P.)	0.020 (T.P.)
D	0.22±0.05	$0.009^{+0.002}_{-0.003}$
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	1.0±0.05	$0.039^{+0.003}_{-0.002}$
I	16.4±0.1	$0.646^{+0.004}_{-0.005}$
J	0.8±0.2	$0.031^{+0.009}_{-0.008}$
K	0.145±0.05	$0.006^{+0.002}_{-0.003}$
L	0.5	0.020
М	0.10	0.004
N	0.10	0.004
Р	18.0±0.2	$0.709^{+0.008}_{-0.009}$
Q	3°+5°	3°+5°
R	0.25	0.010
s	0.60±0.15	$0.024^{+0.006}_{-0.007}$

S48GY-50-MKH1

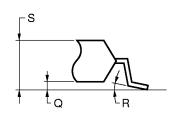


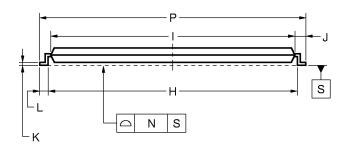
K Version, E Version: Low Standoff Height

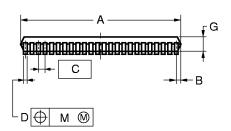
48 PIN PLASTIC TSOP (I) (12x18)



detail of lead end







NOTES

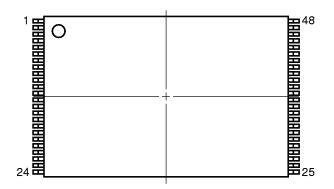
- 1. Controlling dimension millimeter.
- 2. Each lead centerline is located within 0.08 mm (0.003 inch) of its true position (T.P.) at maximum material condition.
- 3. "A" excludes mold flash. (Includes mold flash : 12.4 mm MAX. $<\!0.489$ inch MAX.>)

ITEM	MILLIMETERS	INCHES
Α	12.0±0.1	$0.472^{+0.005}_{-0.004}$
В	0.45 MAX.	0.018 MAX.
С	0.5 (T.P.)	0.020 (T.P.)
D	$0.22^{+0.08}_{-0.07}$	$0.009^{+0.003}_{-0.004}$
G	0.97	0.038
Н	17.0±0.2	$0.669^{+0.009}_{-0.008}$
ı	16.4±0.1	$0.646^{+0.004}_{-0.005}$
J	0.8±0.2	$0.031^{+0.009}_{-0.008}$
K	0.145 ^{+0.03} -0.055	$0.006^{+0.001}_{-0.003}$
L	0.5±0.1	0.020 +0.004 -0.005
М	0.08	0.003
N	0.10	0.004
Р	18.0±0.2	$0.709^{+0.008}_{-0.009}$
Q	0.05±0.05	0.002±0.002
R	2°+4° -2°	2°+4° -2°
s	1.02±0.08	0.040+0.004
_		S48GY-50-MJH-3

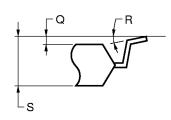


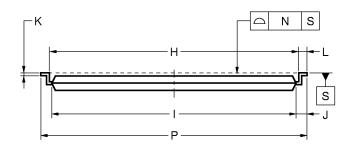
K Version, E Version: Low Standoff Height

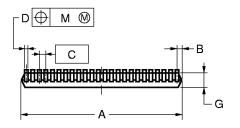
48 PIN PLASTIC TSOP (I) (12x18)



detail of lead end







NOTES

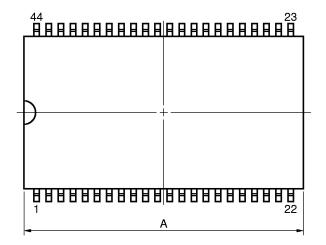
- 1. Controlling dimension millimeter.
- Each lead centerline is located within 0.08 mm (0.003 inch) of its true position (T.P.) at maximum material condition.
- 3. "A" excludes mold flash. (Includes mold flash : 12.4 mm MAX. $<\!0.489$ inch MAX.>)

ITEM	MILLIMETERS	INCHES
А	12.0±0.1	$0.472^{+0.005}_{-0.004}$
В	0.45 MAX.	0.018 MAX.
С	0.5 (T.P.)	0.020 (T.P.)
D	$0.22^{+0.08}_{-0.07}$	$0.009^{+0.003}_{-0.004}$
G	0.97	0.038
Н	17.0±0.2	$0.669^{+0.009}_{-0.008}$
ı	16.4±0.1	$0.646^{+0.004}_{-0.005}$
J	0.8±0.2	$0.031^{+0.009}_{-0.008}$
К	$0.145^{+0.03}_{-0.055}$	$0.006^{+0.001}_{-0.003}$
L	0.5±0.1	0.020 +0.004 -0.005
М	0.08	0.003
N	0.10	0.004
Р	18.0±0.2	$0.709^{+0.008}_{-0.009}$
Q	0.05±0.05	0.002±0.002
R	2°+4° -2°	2°+4° -2°
s	1.02±0.08	$0.040^{+0.004}_{-0.003}$

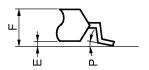
S48GY-50-MKH-3

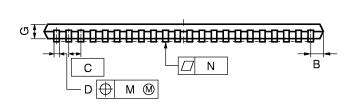


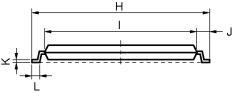
44 PIN PLASTIC TSOP(II) (400 mil)



detail of lead end







NOTE

Each lead centerline is located within 0.13 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
Α	18.63 MAX.	0.734 MAX.
В	0.93 MAX.	0.037 MAX.
С	0.8 (T.P.)	0.031 (T.P.)
D	$0.32^{+0.08}_{-0.07}$	0.013±0.003
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	0.97	0.038
Н	11.76±0.2	0.463±0.008
ı	10.16±0.1	0.400±0.004
J	0.8±0.2	$0.031^{+0.009}_{-0.008}$
К	$0.145^{+0.025}_{-0.015}$	0.006±0.001
L	0.5±0.1	$0.020^{+0.004}_{-0.005}$
М	0.13	0.005
N	0.10	0.004
Р	3°+7°	3°+7°

S44G5-80-7JF5



Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the $\mu PD23C32000L$.

Types of Surface Mount Device

 μ PD23C32000LGX : 44-pin plastic SOP (600 mil)

 μ PD23C32000LGY-MJH : 48-pin plastic TSOP (I) (12 × 18 mm) (Normal Bent) μ PD23C32000LGY-MKH : 48-pin plastic TSOP (I) (12 × 18 mm) (Reverse Bent) μ PD23C32000LG5-7JF : 44-pin plastic TSOP (II) (400 mil) (Normal Bent)



NOTES FOR CMOS DEVICES-

(1) PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note: Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

(2) HANDLING OF UNUSED INPUT PINS FOR CMOS

Note: No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

(3) STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note: Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

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NEC devices are classified into the following three quality grades:

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Standard: Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots

Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)

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Anti-radioactive design is not implemented in this product.